



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

**Quality Inspection Technologies
(Division of 6297986 Canada Ltd)**
6537 Kister Rd., Unit 2
Niagara Falls, ON L2G 0B8 Canada

Fulfils the requirements of

ISO/IEC 17025:2017

In the fields of

**CALIBRATION
and DIMENSIONAL MEASUREMENT**

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

Jason Stine, Vice President

Expiry Date: 05 August 2027

Certificate Number: L1094-1



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

Quality Inspection Technologies

(a division of 297986 Canada, Ltd)

6537 Kister Rd., Unit 2
Niagara Falls, ON L2G 0B8 Canada
Torben Rasmussen
905-354-9507

CALIBRATION AND DIMENSIONAL MEASUREMENT

Valid to: August 5, 2027, Certificate Number: L1094-1

CALIBRATION

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-) ¹	Reference Standard, Method, and/or Equipment
Micrometer Standards	Up to 29 in	(39 + 6L) μ in	Comparison to Gauge Blocks using Telma 500
	(29 to 48) in	(21 + 7.8L) μ in	
Plain Rings	(0.5 to 6) in	(51 + 6D) μ in	Comparison to Gauge Blocks using Telma 500
Pin Gauges	Up to 1 in	(51 + 4.8D) μ in	
Plug Gauges	Up to 4 in	(49 + 5.8D) μ in	
Outside Micrometer (0.000 05 in Resolution)	(0 to 48) in	(38 + 7.1L) μ in	Comparison to Gauge Blocks
Outside Micrometer (0.000 1 in Resolution)	(0 to 48) in	(47 + 6.7L) μ in	
Outside Micrometer (0.001 in Resolution)	(0 to 48) in	(570 + 2.3L) μ in	
Depth Micrometer (0.000 05 in Resolution)	(0 to 12) in	(54 + 5L) μ in	
Depth Micrometer (0.000 1 in Resolution)	(0 to 12) in	(73 + 4.3L) μ in	
Depth Micrometer (0.001 in Resolution)	(0 to 12) in	(580 + 0.7L) μ in	

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-) ¹	Reference Standard, Method, and/or Equipment
Inside Micrometer (0.000 1 in Resolution)	(2 to 29) in	(64 + 7.5L) μ in	Comparison to Gauge Blocks using Telma 500
Inside Micrometer (0.001 in Resolution)	(2 to 29) in	(580 + 2.2L) μ in	Comparison to Gauge Blocks using Telma 500
Inside Micrometer (0.000 1 in Resolution)	(30 to 80) in	(130 + 6L) μ in	Comparison to Gauge Blocks
Inside Micrometer (0.001 in Resolution)	(30 to 80) in	(520 + 4L) μ in	Comparison to Gauge Blocks
Calipers (0.000 1 in Resolution)	(0 to 48) in	(400 + 9.6L) μ in	Comparison to Gauge Blocks
Calipers (0.000 5 in Resolution)	(0 to 48) in	(640 + 7.8L) μ in	Comparison to Gauge Blocks
Dial/Digital Indicators (0.000 1 in Resolution)	(0 to 1) in	(80 + 3.1L) μ in	Comparison to Telma 500
Dial/Digital Indicators (0.000 5 in Resolution)	(0 to 1) in	(300 + 0.9L) μ in	Comparison to Telma 500
Test Indicators (0.000 1 in Resolution)	(0 to 0.4) in	(78 + 25.7L) μ in	Comparison to Telma 500
Test Indicators (0.000 5 in Resolution)	(0 to 0.4) in	(300 + 10.2L) μ in	
Dial Bore Gauges (0.000 1 in Resolution)	(0 to 1) in travel	(91 + 4.8L) μ in	
Height Gauges (0.000 5 in Resolution)	(0 to 48) in	(570 + 3.6L) μ in	Comparison to Gauge Blocks using Mahr Comparator and Surface Plate
Height Gauges (0.001 in Resolution)	(0 to 48) in	(910 + 2.5L) μ in	Comparison to Gauge Blocks using Mahr Comparator and Surface Plate
Steel Rules / Scales	(0 to 36) in	(93 + 13) L μ in	Comparison with Master Steel Rule
Bevel Protractors	Up to 90°	0.005 6°	Comparison to Angle Blocks and Surface Plate

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-) ¹	Reference Standard, Method, and/or Equipment
Thread Plug Gauges			
Major Diameter	Up to 4 in	(52 + 4.2D) μ in	Comparison to Micrometer
Pitch Diameter (60° thread angle)	Up to 4 in	(77 + 9.0D) μ in	Bench Micrometer, Mahr Probe, Thread Wires

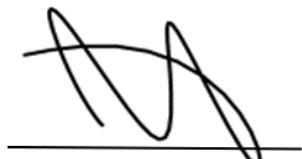
DIMENSIONAL MEASUREMENT
3 Dimensional

Parameter	Range	Expanded Uncertainty of Measurement (+/-) ¹	Reference Standard, Method and/or Equipment
Dimensional Measurement 3D	X = (0 to 47) in Y = (0 to 78) in Z = (0 to 40) in	(97 + 60L) μ in	Measurement using Wenzel Coordinate Measuring Machine

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ($k=2$), corresponding to a confidence level of approximately 95%.

Notes:

1. D = diameter in inches, L = length in inches.
2. This scope is formatted as part of a single document, including Certificate of Accreditation No. L1094-1.



Jason Stine, Vice President